Se	earch Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/549,359	HOSOKAWA ET AL.	
Examiner	Art Unit	·
Matthew D. Matzek	1771	

SEARCHED			
Class	Subclass	Date	Examiner
442	345,347 363	5/31/2007	ММ
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INTERFERENCE SEARCHED			
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	DATE	EXMR
IDS	5/31/2007	ММ
INVENTOR AND ASSIGNEE	5/31/2007	ММ
EAST	5/31/2007	ММ
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